

FDA20N50F N-Channel MOSFET 500V, 22A, 0.26Ω

Features

• $R_{DS(on)} = 0.22\Omega$ (Typ.) @ $V_{GS} = 10V$, $I_D = 11A$

GDS

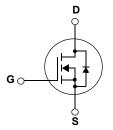
- Low gate charge (Typ. 50nC)
- + Low C_{rss} (Typ. 27pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant



Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These device are well suited for high efficient switched mode power supplies and active power factor correction.



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

TO-3PN

Symbol	Parameter			Ratings	Units	
V _{DSS}	Drain to Source Voltage			500	V	
V _{GSS}	Gate to Source Voltage			±30	V	
I _D	Drain Current	-Continuous ($T_C = 25^{\circ}C$)		22	— A	
	DrainCurrent	-Continuous ($T_C = 100^{\circ}C$)		13		
I _{DM}	Drain Current	- Pulsed	(Note 1)	88	А	
E _{AS}	Single Pulsed Avalanche E	(Note 2)	1110	mJ		
I _{AR}	Avalanche Current		(Note 1)	22	Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	39	mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20	V/ns	
P _D	Devuer Dissignation	$(T_{\rm C} = 25^{\rm o}{\rm C})$		388	W	
	Power Dissipation	- Derate above 25°C		3.1	W/ ^o C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C	

Thermal Characteristics

Symbol	Parameter	Min.	Max.	Units
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	-	0.44	
$R_{\theta CS}$	Thermal Resistance, Case to Sink	0.24	-	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	-	40	

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Device wi	arking	Device Marking Device		qe	Reel Size	Таре	e Width		Quantit	y
		TO-3P	N	-		-		30		
Flectrics	l Char	acteristics T _c =	25°C unless	othenwis	e noted	1				
Symbol		Parameter	Test Conditions		Min.	Тур.	Max.	Units		
Off Charac	cteristic	S		1		I	1			1
BV _{DSS}	Drain to	Source Breakdown \	/oltage	$I_D = 250 \mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$		500	-	-	V	
ΔΒV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient		$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		-	0.6	-	V/ºC		
	Zero Ga	ate Voltage Drain Curr	ent	V _{DS} = 500V, V _{GS} = 0V		-	-	10	μA	
IDSS	2010 00		CIII	V _{DS} = 400V, T _C = 125 ^o C			-	-	100	μΛ
I _{GSS}	Gate to Body Leakage Current		V _{GS} = :	±30V, V _{DS} = 0V		-	-	±100	nA	
On Charac	cteristic	S								
V _{GS(th)}	Gate Threshold Voltage		V _{GS} =	V _{DS} , I _D = 250μA		3.0	-	5.0	V	
R _{DS(on)}	Static Drain to Source On Resistance		V _{GS} =	10V, I _D = 11A		-	0.22	0.26	Ω	
9 _{FS}	Forward Transconductance			$V_{DS} = 4$	40V, I _D = 11A	(Note 4)	-	24	-	S
Dynamic (Characte	eristics								
C _{iss}		apacitance					-	2550	3390	pF
C _{oss}	Output	Capacitance		$V_{DS} = 25V, V_{GS} = 0$		t	-	350	465	pF
C _{rss}	Reverse	e Transfer Capacitanc	e f = 1MHz		.HZ		-	27	40	pF
Q _{g(tot)}	Total Ga	ate Charge at 10V		$V_{DS} = 400V, I_D = 20A$ $V_{GS} = 10V$ (Note 4, 5)		-	50	65	nC	
Q _{gs}	Gate to	Source Gate Charge				-	14	-	nC	
Q _{gd}	Gate to	Drain "Miller" Charge				-	20	-	nC	
	Ohanaa					(11010 4, 0)				
Switching		Delay Time					-	45	100	ns
t _{d(on)}		Rise Time		Vpp =	250V, I _D = 20A		-	120	250	ns
t _r +		Delay Time		$R_{G} = 25\Omega$			-	120	210	-
t _{d(off)}						-	60	130	ns ns	
t _f	Turn-Off Fall Time (Note 4, 5				(NOLE 4, 5)	_	00	100	113	
		le Characteristic			d Current				20	•
l _S	Maximum Continuous Drain to Source Diod				-	-	22	A		
I _{SM}	Maximum Pulsed Drain to Source Diode Fo Drain to Source Diode Forward Voltage		rward Current $V_{GS} = 0V, I_{SD} = 22A$		-	-	88	A		
V _{SD}			d voltage		*-		-	-	1.5	V
	Reverse Recovery Time Reverse Recovery Charge			0V, I _{SD} = 20A 100A/μs	(Note 4)	-	154	-	ns	
Q _{rr}	Reveise	Recovery charge		ai _F /at	100/040	(1000 4)	-	0.5	-	μC

25°C

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*Notes:

25°C

*Notes: 1. V_{GS} = 0V

1.0

2. 250µs Pulse Test

*Note: I_D = 20A

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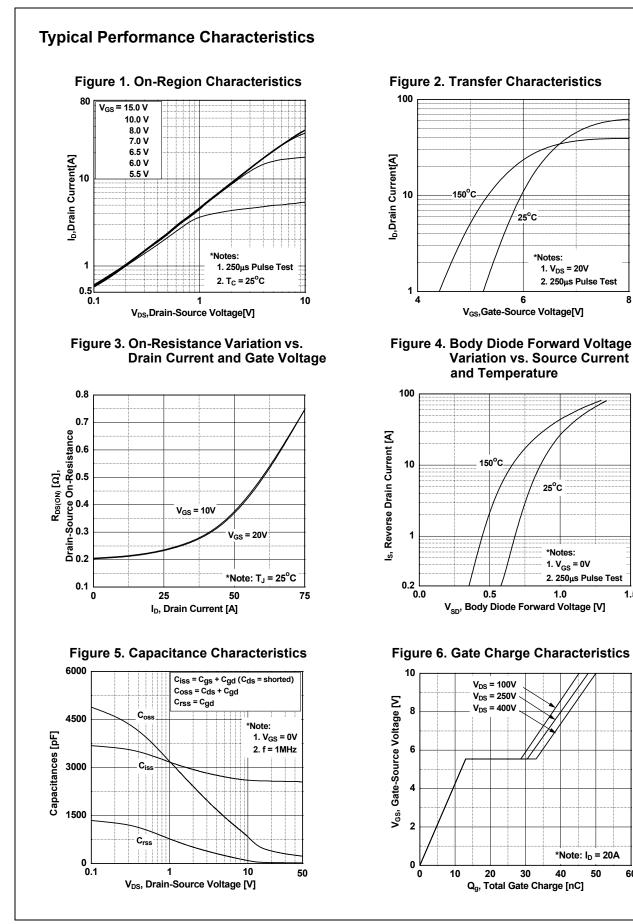
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1.5

1. V_{DS} = 20V

2. 250µs Pulse Test

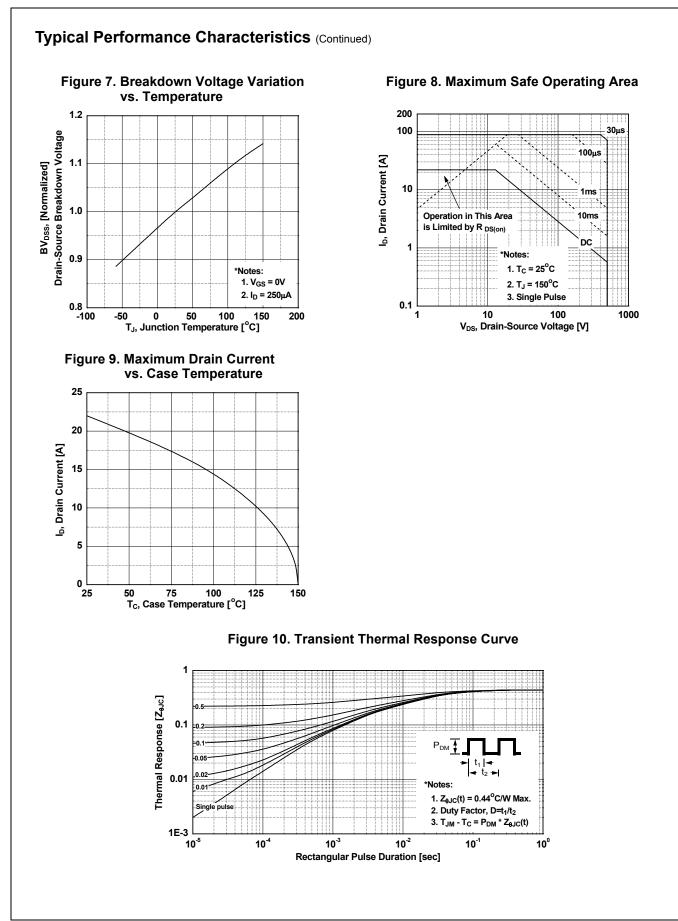
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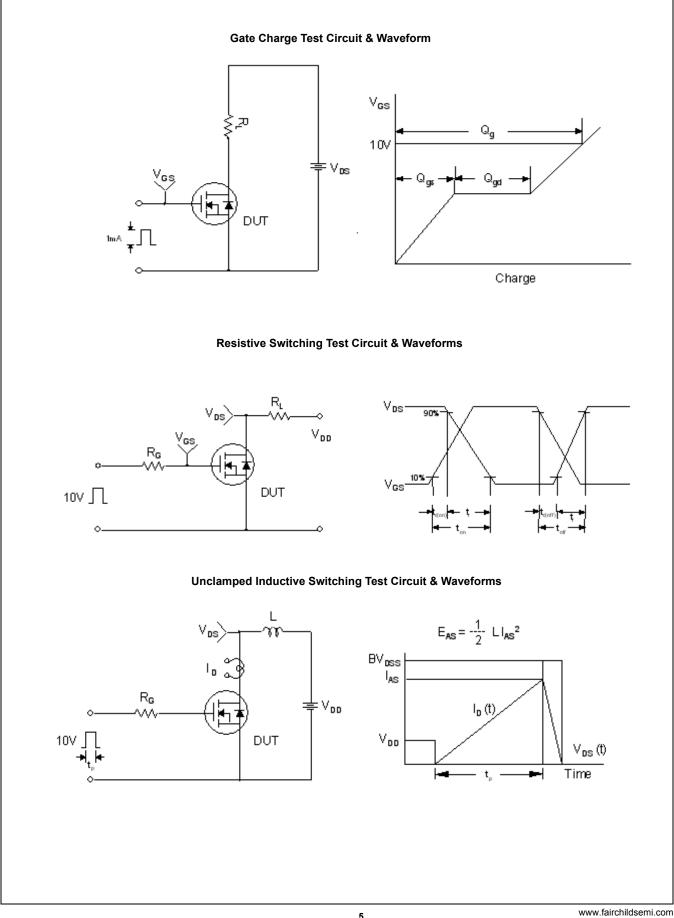
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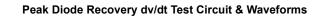
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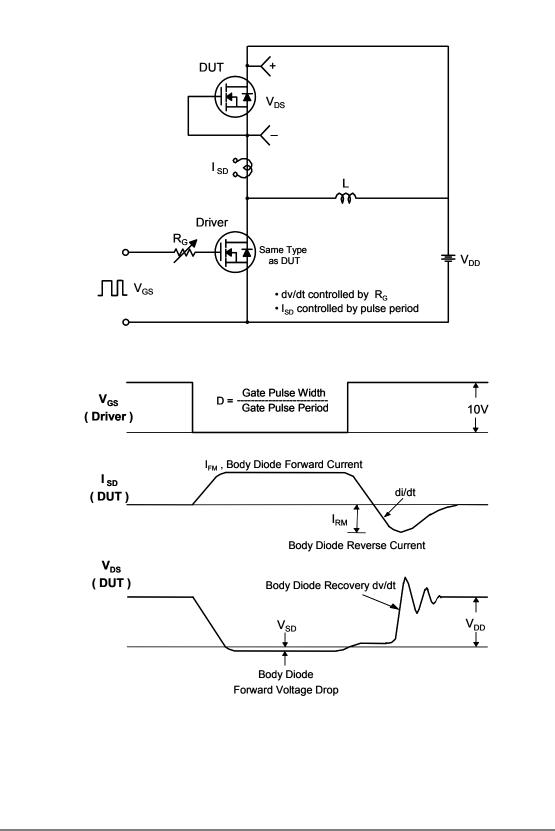


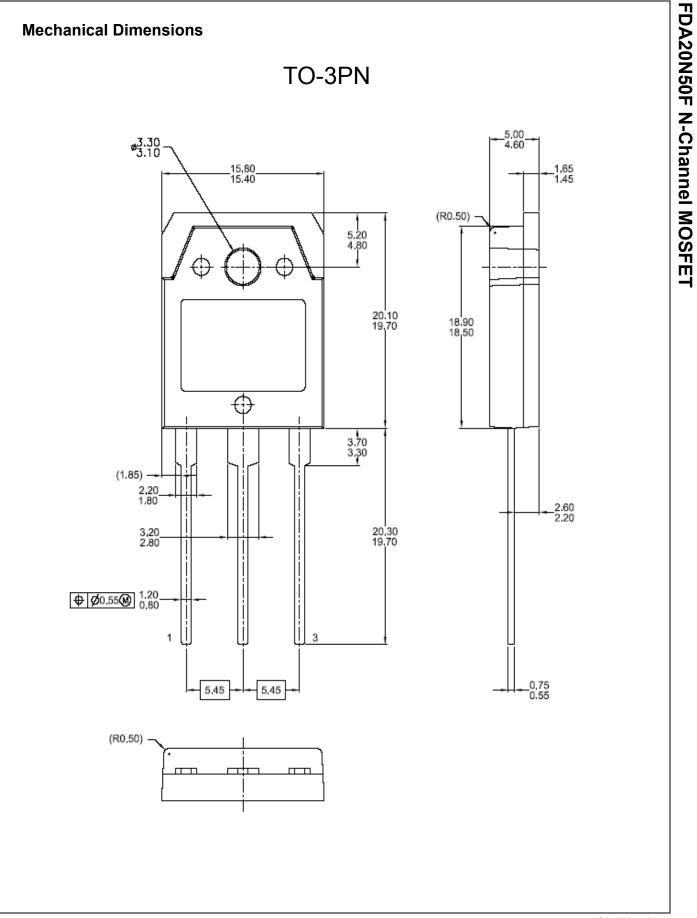
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